


<b>Search Notes</b>  	<b>Application/Control No.</b>  10578512	<b>Applicant(s)/Patent Under Reexamination</b>  FUNKE ET AL.
	<b>Examiner</b>  John Pak	<b>Art Unit</b>  1616

SEARCHED			
Class	Subclass	Date	Examiner
514	341, 462	5/10	JP

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--